## The University of Alabama in Huntsville Electrical and Computer Engineering CPE 633 01 Homework #1 Solution Spring 2008

1. The lifetime (measured in years) of a processor is exponentially distributed, with a mean lifetime of 2 years. You are told that a processor failed sometime in the interval [4, 8] years. Given this information, what is the conditional probability that it failed before it was 5 years old?

Denote the lifetime of the processor by T. Since E(T) = 2,  $\lambda = 0.5$  and the distribution function of T is  $F(t) = 1 - e^{-0.5\lambda t}$ . Using the conditional probability formula: Prob{T < 5 | 4 ≤ T ≤ 8} =

$$\frac{\operatorname{Prob}\{T < 5\} \cap \operatorname{Prob}\{4 \le T < 8\}}{\operatorname{Prob}\{4 \le T < 8\}} = \frac{\operatorname{Prob}\{4 \le T < 5\}}{\operatorname{Prob}\{4 \le T < 8\}} = \frac{F(5) - F(4)}{F(8) - F(4)} = \frac{(1 - e^{-5(0.5)}) - (1 - e^{-4(0.5)})}{(1 - e^{-8(0.5)}) - (1 - e^{-4(0.5)})}$$
$$= \frac{e^{-2} - e^{-2.5}}{e^{-2} - e^{-4}} = 0.455$$

- 2. The lifetime of a processor (measured in years) follows the Weibull distribution, with parameters  $\lambda = 0.5$  and  $\beta = 0.6$ .
  - (a) What is the probability that it will fail in its first year of operation?
  - (b) Suppose it is still functional after t = 6 years of operation. What is the conditional probability that it will fail in the next year?
  - (c) Repeat parts (a) and (b) for  $\beta = 2$ .
  - (d) Repeat parts (a) and (b) for  $\beta = 1$ .

(a) Denote the lifetime of the processor by T. The distribution function of T is

 $F(t) = 1 - e^{-0.5t^{0.6}}$ . The probability that T is no greater than one year is

$$F(1) = 1 - e^{(-0.5)1^{0.6}} = 1 - e^{-0.5} = 1 - 0.606 = 0.394$$

(b) We use the conditional probability formula:

$$\frac{\operatorname{Prob}\{T < 7\} \cap \operatorname{Prob}\{T > 6\}}{\operatorname{Prob}\{T > 6\}} = \frac{\operatorname{Prob}\{6 \le T < 7\}}{1 - F(6)} = \frac{F(7) - F(6)}{1 - 1 - e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)7^{0.6}}) - (1 - e^{-(0.5)6^{0.6}})}{e^{(-0.5)6^{0.6}}} = \frac{e^{-(0.5)6^{0.6}}}{e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)7^{0.6}}) - (1 - e^{-(0.5)6^{0.6}})}{e^{(-0.5)6^{0.6}}} = \frac{e^{-(0.5)6^{0.6}}}{e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)7^{0.6}}) - (1 - e^{-(0.5)6^{0.6}})}{e^{(-0.5)6^{0.6}}} = \frac{e^{-(0.5)6^{0.6}}}{e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)7^{0.6}}) - (1 - e^{-(0.5)6^{0.6}})}{e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)6^{0.6}}) - (1 - e^{-(0.5)6^{0.6}})}{e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)7^{0.6}}) - (1 - e^{-(0.5)6^{0.6}})}{e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)6^{0.6}})}{e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)7^{0.6}})}{e^{(-0.5)6^{0.6}}} = \frac{(1 - e^{-(0.5)7^{0.6}})}{$$

(c) F(1) = 1 - 
$$e^{(-0.5)1^2} = 1 - e^{-0.5} = 1 - 0.606 = 0.394$$
  

$$\frac{\text{Prob}\{T < 7\} \cap \text{Prob}\{T > 6\}}{\text{Prob}\{T > 6\}} = \frac{\text{Prob}\{6 \le T < 7\}}{1 - \text{F}(6)} = \frac{F(7) - F(6)}{1 - 1 - e^{(-0.5)6^2}} = \frac{(1 - e^{-(0.5)7^2}) - (1 - e^{-(0.5)6^2})}{e^{(-0.5)6^2}}$$

$$= \frac{e^{-(0.5)6^2} - e^{-(0.5)7^2}}{e^{(-0.5)6^{0.6}}} = \frac{1.52 \times 10^{-8} - 2.29 \times 10^{-11}}{1.52 \times 10^{-8}} = 1.00$$

(d) 
$$F(1) = 1 - e^{(-0.5)1^{1}} = 1 - e^{-0.5} = 1 - 0.606 = 0.394$$
  

$$\frac{\operatorname{Prob}\{T < 7\} \cap \operatorname{Prob}\{T > 6\}}{\operatorname{Prob}\{T > 6\}} = \frac{\operatorname{Prob}\{6 \le T < 7\}}{1 - F(6)} = \frac{F(7) - F(6)}{1 - 1 - e^{(-0.5)6^{1}}} = \frac{(1 - e^{-(0.5)7^{1}}) - (1 - e^{-(0.5)6^{1}})}{e^{(-0.5)6^{1}}}$$

$$= \frac{e^{-(0.5)6^{1}} - e^{-(0.5)7^{1}}}{e^{(-0.5)6^{1}}} = \frac{0.0498 - 0.0302}{0.0498} = 0.394$$

4. Write the expression for the reliability R<sub>system</sub>(t) of the series/parallel system shown in Figure 2.2, assuming that each of the five modules has a reliability of R(t).



The system can be decomposed into a series system consisting of one unit with the leftmost 4 blocks and the second unit with the rightmost block. If the reliability of the leftmost 4 blocks is  $R_A(t)$ , the system reliability is  $R_A(t)R(t)$ . Now, we calculate  $R_A(t)$ . This subsystem consists of a parallel arrangement of one unit consisting of the bottom block and another consisting of the other 3 blocks. If  $R_B(t)$  is the reliability of the top 3 blocks,  $R_A(t) = 1 - (1 - R_B(t))(1 - R(t))$ . Next, we calculate  $R_B(t)$ : this subsystem consists of a series arrangement of one block with another consisting of two blocks in parallel. Hence, we have

 $R_{B}(t) = R(t)(1 - (1 - R(t))^{2}) = R(t)(1 - (1 - 2R(t) + R^{2}(t))) = R(t)((2R(t) - R^{2}(t)) = 2R^{2}(t) - R^{3}(t)$ 

$$\begin{split} R_A(t) &= 1 - (1 - (2R^2(t) - R^3(t)))(1 - R(t)) \\ &= 1 - (1 - 2R^2(t) + R^3(t))(1 - R(t)) \\ &= 1 - (1 - R(t) - 2R^2(t) + 2R^3(t) + R^3(t) - R^4(t) \\ &= R(t) + 2R^2(t) - 3R^3(t) + R^4(t) \end{split}$$

 $R_{system} = R_A(t)R(t) = R^5(t) - 3R^4(t) + 2R^3(t) + R^2(t)$ 

- 12. Consider a system consisting of 2 subsystems in series. For improved reliability, you can build subsystem i as a parallel system with ki units, for i = 1, 2. Suppose permanent failures occur at a constant rate  $\lambda$  per unit.
  - (a) Derive an expression for the reliability of this system.
  - (b) Obtain an expression for the MTTF of this system with  $k_1 = 2$  and  $k_2 = 3$ .
  - (a) The reliability of a parallel system with k units is  $R_p^{(k)}(t) = 1 (1 e^{-\lambda t})^k$ . Hence, the releiability

of the series system is given by  $R_{series} = R_p^{(k_1)}(t)R_p^{(k_2)}(t)$ (b) For  $k_1 = 2$  and  $k_2 = 3$ ,

$$\begin{split} R_{p}^{(k_{1})}(t) &= 1 - (1 - e^{-\lambda t})^{k_{1}} = R_{p}^{(2)}(t) = 1 - (1 - e^{-\lambda t})^{2} = 1 - (1 - 2e^{-\lambda t} + e^{-2\lambda t}) = 2e^{-\lambda t} - e^{-2\lambda t} \\ R_{p}^{(k_{2})}(t) &= 1 - (1 - e^{-\lambda t})^{k_{2}} = R_{p}^{(3)}(t) = 1 - (1 - e^{-\lambda t})^{3} = 1 - ((1 - 2e^{-\lambda t} + e^{-2\lambda t})(1 - e^{-\lambda t})) \\ &= 1 - (1 - e^{-\lambda t} - 2e^{-\lambda t} + 2e^{-2\lambda t} + e^{-2\lambda t} - e^{-3\lambda t}) = 3e^{-\lambda t} - 3e^{-2\lambda t} + e^{-3\lambda t} \\ R_{series} &= (2e^{-\lambda t} - e^{-2\lambda t})(3e^{-\lambda t} - 3e^{-2\lambda t} + e^{-3\lambda t}) = 6e^{-2\lambda t} - 6e^{-3\lambda t} + 2e^{-4\lambda t} - 3e^{-3\lambda t} + 3e^{-4\lambda t} - e^{-5\lambda t} \end{split}$$

$$= 6 e^{-2\lambda t} - 9 e^{-3\lambda t} + 5 e^{-4\lambda t} - e^{-5\lambda t}$$

$$MTTF = \int_{t=0}^{\infty} R_{series}(t) dt = \int_{t=0}^{\infty} (6e^{-2\lambda t} - 9e^{-3\lambda t} + 5e^{-4\lambda t} - e^{-5\lambda t})(t) dt$$

$$= \frac{6}{-2\lambda} e^{-2\lambda t} - \frac{9}{-3\lambda} e^{-3\lambda t} + \frac{5}{-4\lambda} e^{-4\lambda t} - \frac{1}{-5\lambda} e^{-5\lambda t} \Big|_{t=0}^{\infty}$$

$$= \left[ \frac{6}{-2\lambda} e^{-2\lambda \infty} - \frac{9}{-3\lambda} e^{-3\lambda \infty} + \frac{5}{-4\lambda} e^{-4\lambda \infty} - \frac{1}{-5\lambda} e^{-5\lambda \infty} \right] - \left[ \frac{6}{-2\lambda} e^{-2\lambda 0} - \frac{9}{-3\lambda} e^{-3\lambda 0} + \frac{5}{-4\lambda} e^{-4\lambda 0} - \frac{1}{-5\lambda} e^{-5\lambda 0} \right]$$

$$= \left[ 0 - 0 + 0 - 0 \right] - \left[ -\frac{6}{2\lambda} + \frac{9}{3\lambda} - \frac{5}{4\lambda} + \frac{1}{5\lambda} \right] = \frac{3}{\lambda} - \frac{3}{\lambda} + \frac{5}{4\lambda} - \frac{1}{5\lambda} = \frac{25 - 4}{20\lambda} = \frac{21}{20\lambda}$$

14. Write expressions for the upper and lower bounds and the exact reliability of the non series/parallel system shown in Figure 2.6 (denote by R<sub>i</sub>(t) the reliability of module i). Assume that D is a bi-directional unit.



The paths are: AE, BE, CF, ADF, BDF and CDE.

The upper bound is

$$R_{system} \le 1 - (1 - R_A R_E)(1 - R_B R_E)(1 - R_C R_F)(1 - R_A R_D R_F)(1 - R_B R_D R_F)(1 - R_C R_D R_E)$$

The minimal cut sets are: EF, ABC, CDE and ABDF. The lower bound is

 $\begin{aligned} R_{system} &\geq [1 - (1 - R_E)(1 - R_F)][1 - (1 - R_A)(1 - R_B)(1 - R_C)] \ [1 - (1 - R_C)(1 - R_D)(1 - R_E)][1 - (1 - R_A)(1 - R_B)(1 - R_D)(1 - R_C)] \\ R_F)] \end{aligned}$ 

To calculate the exact reliability we expand about module D. If D is faulty A and B are connected in parallel, and then in series with E and all these are in parallel to the series connection of C and F yielding

Rsys| D is faulty = 1 -  $[1 - (R_A + R_B - R_A R_B)R_E](1 - R_C R_F)$ If D is fault-free, A, B and C are connected in parallel, and then in series with the parallel connection of E and F yielding

$$\begin{split} Rsys|D \text{ is fault-free} &= [1 - (1 - R_A)(1 - R_B)(1 - R_C)][R_E + R_F - R_ER_F] \\ Finally, R_{system} &= R_DRsys|D \text{ is fault-free} + (1 - R_D)Rsys|D \text{ is fault} \end{split}$$

 $= R_{\rm D}[1 - (1 - R_{\rm A})(1 - R_{\rm B})(1 - R_{\rm C})][R_{\rm E} + R_{\rm F} - R_{\rm E}R_{\rm F}] + (1 - R_{\rm D}) 1 - [1 - (R_{\rm A} + R_{\rm B} - R_{\rm A}R_{\rm B})R_{\rm E}](1 - R_{\rm C}R_{\rm F})$